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## Scanning Electron Microscopy

- FEI Apreo C Low-Vac
- FEI SCIOS Dual-Beam SEM/FIB
- Hitachi S-3400N

## Capabilities

- Low Vac imaging of non-conductive samples
- Sectioning with Focused Ion Beam
- Elemental Analysis (EDX)
- EBSD
- E-beam Lithography
- STEM



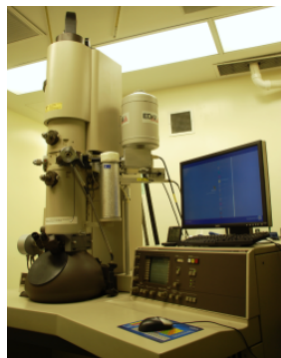
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## Other Characterization Tools



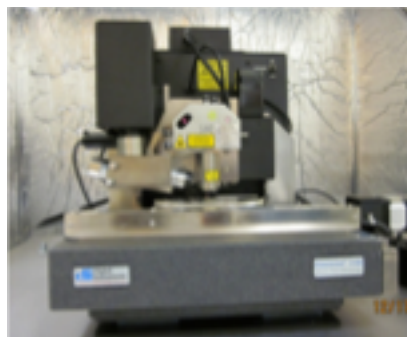
### Differential Scanning Calorimeter

- -90 to 550C
- Auto Sampler
- TGA available in private lab



### Transmission Electron Microscopy

- CM-20 200Kv LaB6
- Elemental Analysis



### Atomic Force Microscopy

- Dimension D-3100
- Wet-Cell
- Contact/Tapping



### X-Ray Diffraction

- Panalytical XRPD
- ICDD PDF 4 Database
- Jade software



### Light Microscopy

- LV150 Nikon
- Brightfield/Darkfield
- Polarizer
- Reflected light
- Metallurgical
- Image Acquisition System

## West Campus Cores

<b>Mass Spectrometry Facility</b>	<b>Environmental Analysis Service Center (EASC)</b>
<b>X-ray Crystallography Facility</b>	<b>Advanced Materials Characterization Center (AMCC)</b>
<b>Nuclear Magnetic Resonance (NMR) Facility</b>	<b>ERC Clean Room</b>
<b>Chemical Sensors &amp; Biosensors Instrumentation Facility</b>	<b>Ohio Center for Microfluidic Innovation (OCMI)</b>
<b>Plasma Spectrochemical Analysis and Metallomics Center</b>	<b>Digital Fabrication Lab</b>
<b>Confocal Microscope Core</b>	